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Chemical effects correlated to nitrogen content of iron nitride films observed in the Fe L-shell X-rays induced by 5-keV electrons

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ABSTRACT

Iron nitride thin films, produced by reactive magnetron sputtering, were characterized with grazing incidence X-ray diffraction, X-ray reflectometry, Rutherford backscattering spectrometry (RBS) and conversion electron Mössbauer spectroscopy. Their characteristic L-X-rays spectra, obtained with an electron microprobe analyzer equipped with a wavelength dispersive spectrometer, were compared to the spectrum of an iron standard. The spectra from the nitrides presented several chemical effects: change in the relative peak areas and shifts of the positions of the $L\alpha_{1,2}$ and the $L\beta_1$ peaks (chemical shift). The change in relative peak areas, namely the ratio between the $L\beta_1$ and the $L\alpha_{1,2}$ peaks, correlated well with the nitrogen content measured with RBS.

1. Introduction

Iron nitride phases have been studied for a long time, due to their application in magnetic recording and because of their wear reducing properties when used as protective surface coatings. Iron nitrides can be obtained by various methods. It has been shown that reactive magnetron sputtering can produce phases encompassing the whole composition range in the phase diagram, even disclosing new phases and structures [1,2].

When nitrogen is a next neighbor to the iron atom, it influences the energy levels and the occupation of the outer electron shells of the iron atoms, reflecting on the X-rays emitted after core ionizations due to transitions that involve the valence electrons.

Chemical effects on the characteristic X-rays were perceived quite early [3–5], and the discovery and interpretation of the shifts in the X-ray spectra since the early 1920s were reviewed by Lindgren [6]. In X-ray spectroscopy, mainly the change in the $K\alpha/K\beta$ ratio of the characteristic X-rays of transition metals are reported [7–15]. The L-shell X-rays are affected as well, but have been less analyzed [16–19], as well as the satellite lines [20,21], and the absorption edges [22].

Many efforts have been made to distinguish the oxidation state of iron in minerals using the chemical effect [23], or the X-ray absorption near edge structure (XANES) [24], but only a few studies were related to other ligands of the iron atom than oxygen [3,4,9,13,15].

The electronic shells of free iron atoms are filled until [Ar] $3d^{5+1-}$ $4s^{1+1-}$ [25], while ideally Fe^{3+} corresponds to [Ar] $3d^{5+}$ and Fe^{2+} to [Ar] $3d^{5+1-}$. In iron metal, however, the mean density of states becomes [Ar] $3d^{4.8+,2.6-}$ $4s^{0.3+,0.3-}$ [25]. Many stoichiometric and non-stoichiometric nitrides are possible, e.g. ε-$Fe_{2-3}N$, γ'-Fe_4N, and $\gamma''/\ \gamma'''$FeN. Nagakura, while studying iron nitrides, determined the electronic occupation of the shells, e.g. of $\gamma'Fe_4N$ as Fe $(Fe^{+1/3})_3N^{-1}$ [26], using the superstructure intensities in electron diffraction patterns. With nuclear reactionanalysis the analysis of nitrogen content is restricted to films with thickness below 200 nm [27]. With EPMA, as in this work, the chemical effect on the iron L-lines can be used to estimate the nitrogen content up to film thicknesses of 500 nm, using 5 keV electrons and considering their range and ability to ionize the iron-L-shell [28].

In this work we report on the findings that several chemical effects on the Fe-L X-ray emissions relate to the nitrogen content in ~20 nm iron nitride layers deposited by reactive magnetron sputtering, using atmospheres with different ratios of N_2/Ar.

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2. Materials and methods

2.1. Sample preparation

Iron nitride films were deposited on silicon wafers as well as on vitreous carbon planchets (Ted Pella) using reactive magnetron sputtering in a ultra-high vacuum equipment (AJA International model ATC, ORION 8 UHV): one film (Fe_xN_yh) in a high N_2 atmosphere (80 vol.% N_2: 20 vol.% Ar) and the other (Fe_xN_yl) in a low N_2 content atmosphere (40 vol.% N_2: 60 vol.% Ar). The gas flows were controlled by two independent mass-flow controllers and adjusted to a total of 25 sccm (standard cubic centimeter). The deposition rate was kept at 2 nm/min, and deposition time was 10 min for both films. The deposition occurred at room temperature without further annealing. The characterizations were performed either on the films on top of the silicon wafer or on the carbon planchets.

2.2. Sample characterization

The samples were analyzed with grazing incidence X-ray diffraction (GIXRD) in Seeman Bohlin geometry using 0.5° incidence angle, in the 2θ range from 20° to 70° (Shimadzu XRD6000, with Cu-tube and thin film attachment). The diffractograms were interpreted with the cards from the powder diffraction file (PDF-2) and the grain size determined using the Scherrer formula, when peaks were observable.

The X-ray reflectivity (XRR) was measured in the same XRD6000 equipment in Bragg–Brentano geometry, in the 2θ range from 0.5° to 5°. The Xpert reflectivity software (Panalytical) was used for thickness determination.

The thickness and composition was analyzed with Rutherford backscattering spectrometry (RBS) in a 3 MV Tandetron (High Voltage Engineering), using alpha particles accelerated to 1 MeV. The code SIMNRA [29] was used to fit the experimental results and to obtain the mass thickness and composition.

Conversion electron Mössbauer spectroscopy (CEMS) was performed in backscattering geometry (Wissel spectrometer) using a ^{57}Co in Rh source to excite the ^{57}Fe atoms in the sample. The hyperfine parameters (magnetic field, isomer shift, and quadrupole splitting) were adjusted using the software Wfitting.

2.3. L-X-ray spectra

The Fe-L-lines from the two films and a bulk iron standard were acquired using an electron probe micro-analyzer (EPMA JEOL JXA 8230) equipped with a wavelength dispersive spectrometer (WDS) containing a TAP (1011) analyzing crystal ($2d$ = 25.76 Å). The beam energy was kept at 5 keV. The spectra were processed subtracting the linear background and fitting the lines with 5 Lorentzian peaks (Origin6®).

3. Characterization

3.1. Grazing incidence X-ray diffraction (GIXRD)

The diffractograms showed that the films had low crystallinity, with broad peaks. While the sample Fe_xN_yh seemed amorphous, it was possible to estimate the grain size of sample Fe_xN_yl to be ~7 nm. The possible phases in this sample were identified as FeN (PDF number 50-1087), Fe_2N (PDF number 76-0090), $Fe_{2-3}N$ (PDF number 86-1025), and contamination with magnetite (PDF number 76-1849).

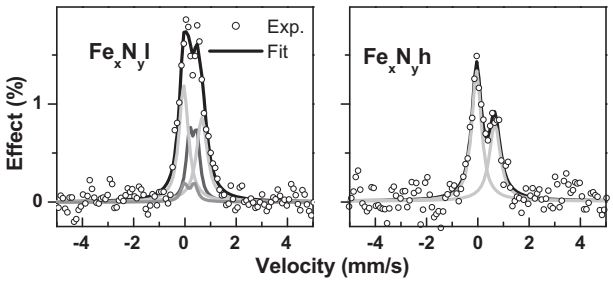

Fig. 1. CEMS of the nitrided samples. Open symbols are the experimental data, black solid lines are the sum of the partial spectra (see Section 3.4).

3.2. X-ray reflectivity (XRR)

The thicknesses of the nitrided layers were estimated with the aid of the X-ray reflectograms. The Fourier transforms of the XRR patterns indicated a strong peak at 18 nm for sample Fe_xN_yh and 17 nm for Fe_xN_yl. The uncertainty in the thickness value was estimated from the width of the Fourier transform. Each oscillation was analyzed individually as well, and the mean thickness and standard deviation were consistent with the values obtained in the Fourier analysis.

3.3. Rutherford backscattering spectrometry (RBS)

RBS measurements showed the presence of iron, nitrogen and oxygen on the carbon substrate. Fe_xN_yl showed a small contamination with sulfur, due to a handling mishap. Simulations with the software SIMNRA indicated a mass thickness of $163{\cdot}10^{15}$ at/cm^2 for Fe_xN_yh and of $187{\cdot}10^{15}$ at/cm^2 for Fe_xN_yl. The N/Fe ratio was 0.88 for Fe_xN_yh and 0.56 for Fe_xN_yl, however the uncertainty associated with the nitrogen analyses was around 30%.

3.4. Conversion electron Mössbauer spectroscopy (CEMS)

The CEMS spectra for the two iron nitride thin films are displayed in Fig. 1. Both CEMS patterns presented an asymmetric double peak, representing nonmagnetic phases. Fe_xN_yh was fitted with the two components of γ″/γ″FeN [30]: (i) a singlet with an isomer shift of 0.06 mm/s and area fraction of 59%, associated to Fe in tetrahedral N coordination; (ii) a singlet with isomer shift of 0.55 mm/s and area fraction of 41%, attributed to the contribution of defects and vacancies in the same structure. In the Fe_xN_yl spectrum the asymmetry was lower and the spectrum did not fit with the γ″/γ″FeN singlets alone, but needed the addition of thetwo doublets of the ε-$Fe_{2.1}$N [31]. The CEMS spectra were able to discriminate the nitride phases, even in the Fe_xN_yh sample, that appeared amorphous in GIXRD. The difference between the crystallinity of the two films, however, was reflected as well in the broader peaks of the CEMS spectra of sample Fe_xN_yh. In Fig. 1 the γ″/γ″FeN singlets are shown in light grey and the ε-$Fe_{2.1}$N doublets in dark grey.

4. Results and discussion

The bonding to a ligand causes an effect on those L-shell X-rays of the iron atom that are produced when the hole in the L-shell is supplied by electrons that participate in the bonding, as are the 3d or 4s electrons. To remind the reader of the structure of the energy levels and the possible electronic transitions, a diagram with the